

Accomplishing PROMISE, PROgrammable MIxed Signal ASIC Electronics Framework

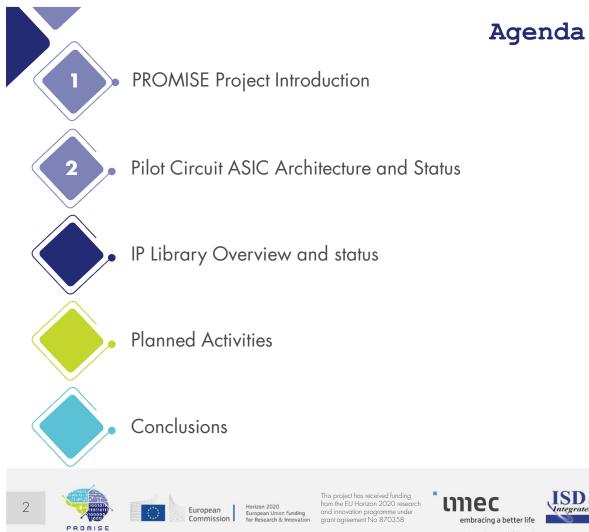
AMICSA - June 2nd, 2022

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100000 PROMISE











PROMISE Project Introduction



European Commission PROMISE

This project has received funding from the EU Horizon 2020 research Horizon 2020 from the EU Horizon 2020 research European Union Funding for Research & Innovation grant agreement No 870358







PROPRIETARY INFORMATION

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PROMISE Consortium

- 7 Institutions
- **6 European countries**
 - Main user (TAS in France and TAS in Spain)
 - Library and IP provider (IMEC)
 - Several IP providers (MENTA, IT, VTT and ISD).
- Well balanced:
 - 2 Large Enterprises
 - 1 Academic partner
 - 3 SMEs
 - 1 Research center
- One Goal: All-European Mixed-signal ASIC for **Space applications**



Horizon 2020 European European Union funding Commission for Research & Innovation

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Integrated Systems Development

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ISD S.A.

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Space

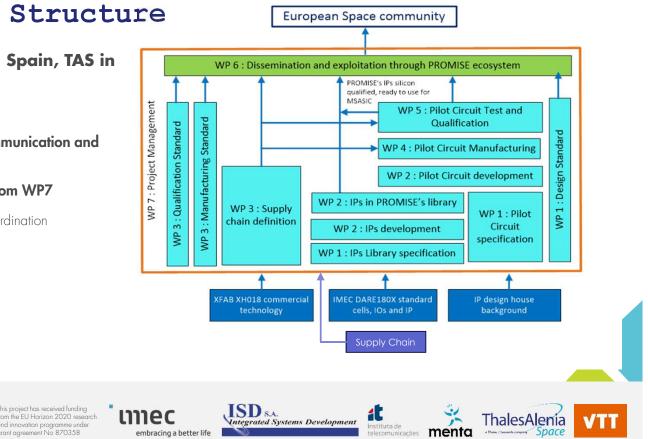


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PROMISE Project Structure

- 7 Work Packages led by TAS in Spain, TAS in France, ISD and IMEC
 - 5 of them technical
 - WP6 dedicated to dissemination, communication and exploitation
 - Overall project coordination driven from WP7
 - Project management and Technical coordination
 - Started in January 2020 -
 - Duration: 4 years
 - PROMISE Webpage:
 - https://promise-h2020.eu/





Mission profile

✓ Supplies :

- ✓ Low voltage (Digital Core and analog) power supply : 1.8V +/-10%
- ✓ Digital IOs and Analog power supply : 3V3 -5%/+10%

Junction temperature :

- ✓ TJfuncmin=-40°C and TJfuncmax=125°C
- ✓ TJperfmin=-20°C and TJperfmax=+105°C

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✓ Life Time :

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- ✓ Based on XFAB corners and derating curves : 100khours
- ✓ No ageing model available

✓ TID :

✓ 100 krad (tested at low dose rate between 36Rad(Si)/h and 360Rad(Si)/h)

✓ SEE :

- \checkmark SEL, MBU and SEFI immune up to a LET of 60MeV.cm²/mg at the maximum functional temperature
- ✓ SEU rate goal less than 10-8 Ev/day/FF (or memory point)
- \checkmark SET error rate at IP level shall be less than 10-8 Ev/day/block on GEO orbit

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HV features

✓ Evaluation for SEGR and SEB safe operating area up to a LET of 60MeV.cm²/mg

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Pilot Circuit Architecture & Status





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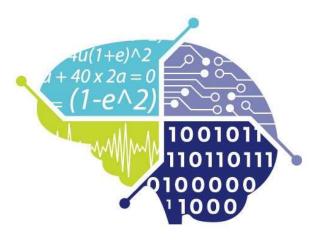
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Pilot Circuit Purpose

- Design a circuit to integrate IPs designed during
 PROMISE project
- Support electrical and radiation tests
 - \checkmark For design validation
 - \checkmark For silicon qualification
- To made qualified and validated IPs available and reusable for the European Space community





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Top level functionalities

- POR, BG, LDO and LO for safe powerup of the Pilot Circuit.
- Analog ressources : DAC, ADC
- Standard AMBA bus.
- Digital core and PLL
- Analog DFT : monitoring analog by multiplexor accessible through SPI in test mode.
- Pilot Circuit POR eFPGA ADC BG DFT DAC PLL NVM SPI/AMBA Master ADC bus AMBA Bus ADC bus DAC bus SPL Master Slave
- ✓ Hardened Standard Cells (LP and LVT)
- ✓ I/O and Bondpads

eFPGA + NVM, the core of ASSP

- ✓ HV features test structure
- Specific test structure for LVDS transceivers

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- NVM for eFPGA bitstream and configuration.
- Digital DFT (SCAN and JTAG) : covers all digital blocks and eFPGA.

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Functional	modes		Lest_mode=1' and rst_n=1'
	Inputs	125	(load_efoga=0' and ip_config=10)
	Outputs	102	(vac_enga=o ano p_comg=o) (sReadVVM) (2)
	Macros	9	
EFPGA	Sequential cells	3050	p_config_dome='1' and (load efboa='0' or ip_config_config_')
	Combinational cells	10319	efpga_control='1' [(bad_efpga='0' or ip_confg_cmd='1'] 3 [load_efpga='1']
	Scan Chains (~length)	8 (500)	sEFPGA control control
BG PLL	Scan Flip-Flops	3002	3 (1) [in_config_cmd='1] (1) [ioad_efpga='1' and]
	ATPG Stuck-at-Faults (coverage)	86288 (95%)	etpga_contol="0"
	Clock domains	16	
ADC DAC LDO	Main operating frequency	16MHz	spi_mode = eFPGA control spi_mode = SPI control spi_mode = disable APB_master_sei = eFPGA APB_master_sei = Command Controller Spi_mode = disable
I_EXTERN_CFG_<1:0>	Mode		Comments
00	Normal		oEPCA IO's are routed to external IO pads

00 Normal eFPGA IO's are routed to external IO pads External eFPGA configuration 01 eFPGA config signals are routed to external IO pads NVM programming signals are routed to external 10 External NVM programming pads 11 LVDS RX Fail-Safe status Output LVDS RX fail-safe status



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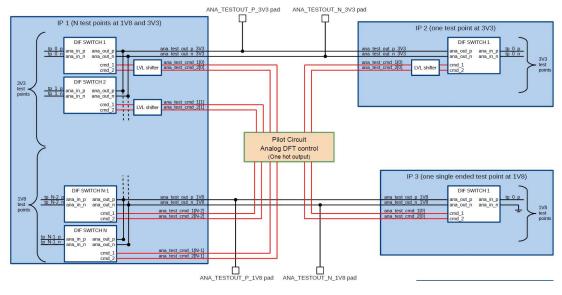
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Analog & Digital DFT strategy

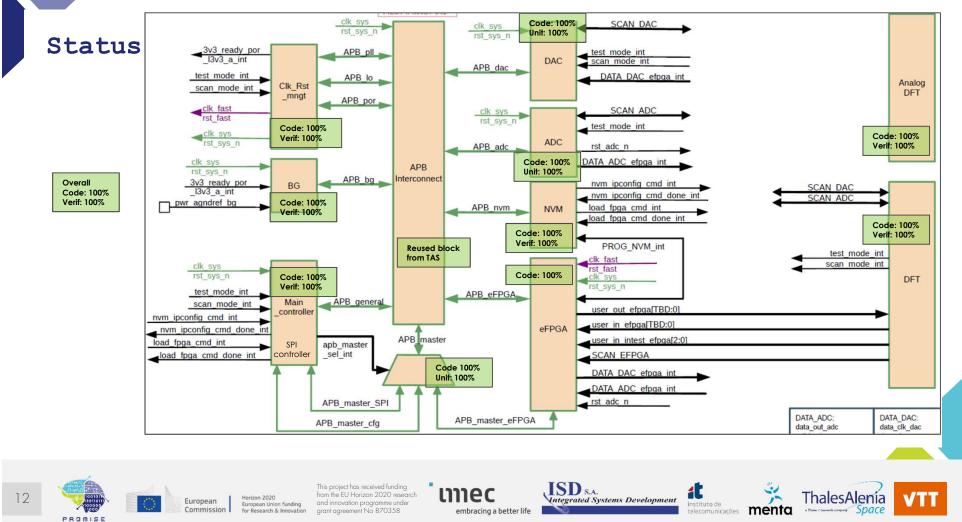


Each blue box represents an IP. All schematics inside a blue box must be implemented inside the corresponding IP. * NVM has specific signals for Analog DFT DFT Modes

TI_TEST_MODE[2:0]	Mode
000	Functional
001	Test-mode
010	Scan-mode pilot circuit
011	Scan-mode eFPGA compressed
101	Scan-mode eFPGA uncompressed
100	Boundary Scan

- Each IP / TOP has its own SCAN interface:
 - Scan-mode, scan-en are common
- ATPG patterns are generated for each IP / TOP independently
- 8 scan-chains: each ~ 500 flops
- ATE clock frequency:10MHz









IP Library **Overview & Status**



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IP eFPGA ID card



Functional description

- eFPGA IP of ~1750 LC + 3 DSP similar to Microsemi RTSX32
- Radiation-hardened
- Based on DARE180X heritage and PROMISE rad-hard standard cells from IMEC
- Specific radiation hardened cells to improve density
- Origami Programmer: Menta state-of-the-art eFPGA EDA RTL to bitstream tool

Main characteristics

- Equivalent number of logical cells = 1751
- Number of DSP : 3 DSP
- Pre-adder/Multiplier size : 24 bit
- DSP ALU size 48 bits
- Number of clocks : 3





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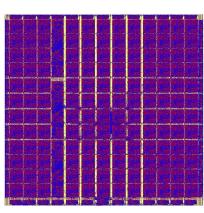
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eFPGA IP architecture

I/O Bank

I/O Ban

LUT

Config I / 0

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eFPGA IP layout

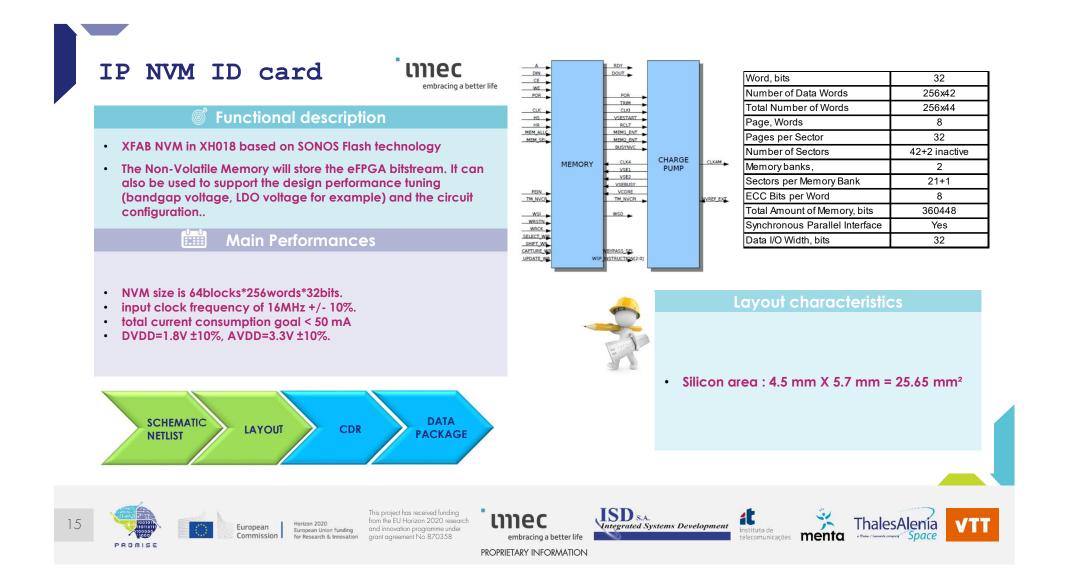
Layout characteristics

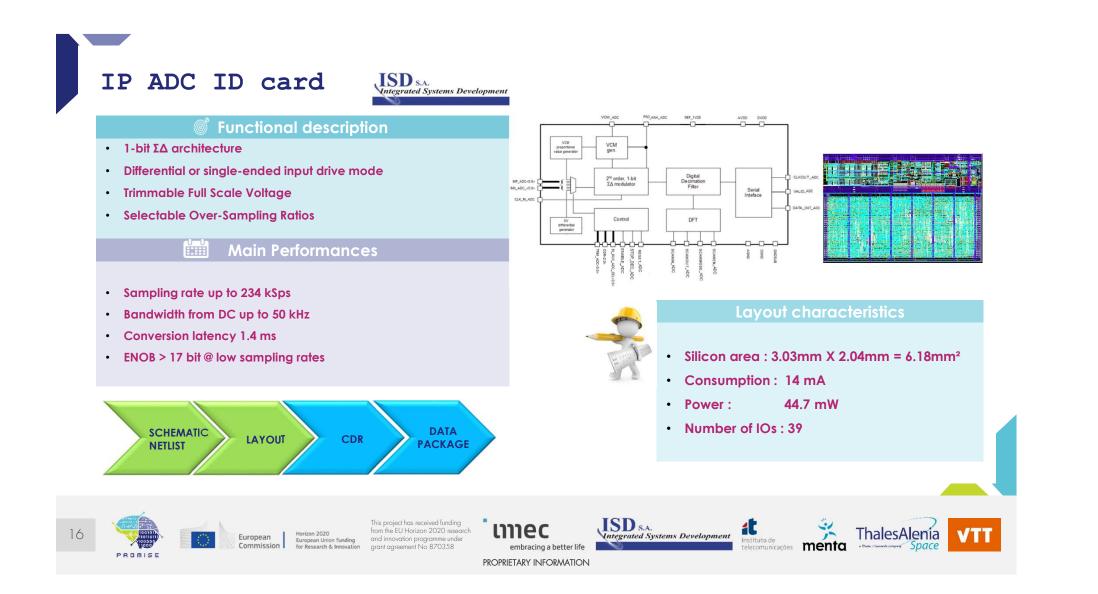
• Silicon area : 8.98 mmX10,12 mm=90.88 mm²

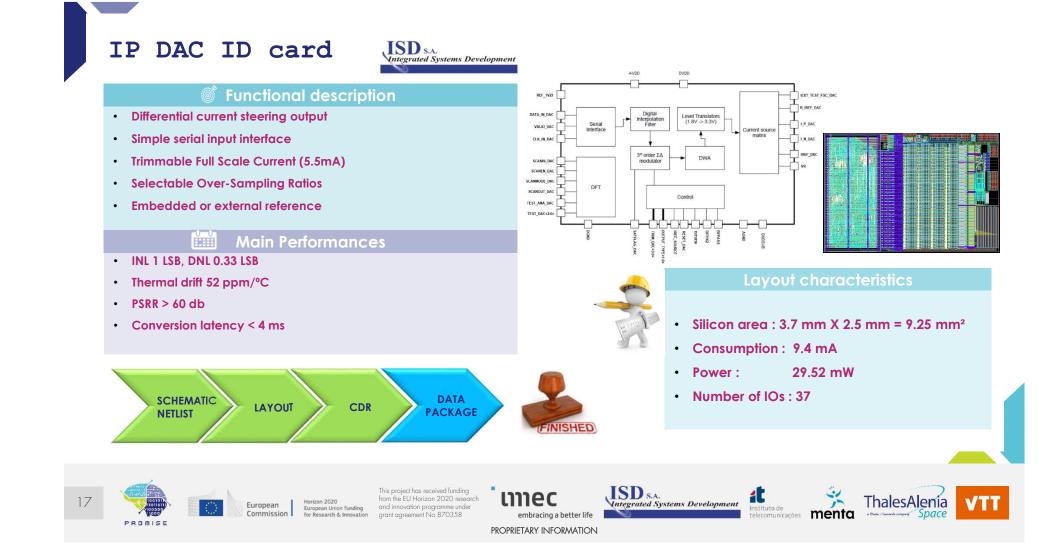
Consumption : bitstream dependant

• Number of IOs : 391/395 (IN/OUT)

Static Power: 1 mW







Status

✓ 90% done

✓ 80% CDR done



IP	SRR	PDR	DDR	Layout	CDR
	(Spec review)	(architecture, schematic and simulation plan)	(Final schematic, simulation at schematic level done)	review	
hvmos	Done	Done	Done	Done	Done
NVM	Done	Done	Done		
Standard cells	Done	Done	Done	Done	Done
POC	Done	Done	Done	Done	Done
Level shifters	Done	Done	Done	Done	Done
IOs	Done	Done	Done	Done	Done
LVDS	Done	Done	Done	Done	Done
POR	Done	Done	Done	Done	Done
BANDGAP	Done	Done	Done	Done	Done
LO	Done	Done	Done	Done	Done
ADC	Done	Done	Done	Done	
DAC	Done	Done	Done	Done	Done
PLL	Done	Done	Done	Done	Done
LDO	Done	Done	Done	Done	Done
eFPGA	Done	Done	Done	Done	Done
Pilot Circuit	Done	Done	Done		



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PROMISE Project Planned Activities



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Pilot Circuit Test and Qualification

Final step of the design, production and validation chain

 Electrical, radiation and silicon qualification tests on the Pilot Circuit □ Assess the space worthiness of the Pilot Circuit Provide silicon qualification status of PROMISE IPs

Task 5.1: Test Board Design and Manufacturing - IN PROGRESS

Development of Test setup: all the elements of the ASIC and measure its performances under laboratory, temperature, radiation....

D5.2 : Electrical Validation plan D5.3 : Radiation Validation plan (TID + SEE) D5.4 : Test board datapackage

Task 5.2: Electrical and radiation tests of Pilot Circuit Run 1 - Participants: TASF, MENTA, VTT - Facilities & beam foreseen by Q2-23.

Test the electrical and radiation performances consistency with the IPs and Pilot Circuit requirements.

D5.5 : Electrical Validation report D5.6 : Radiation Validation report



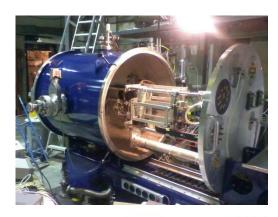
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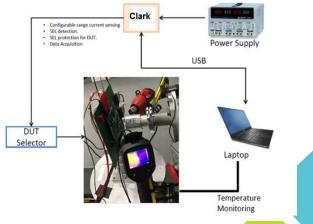


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Task 5.3 Qualification of Pilot Circuit

Leader: TASF/Supply Chain - Participants: VTT, MENTA

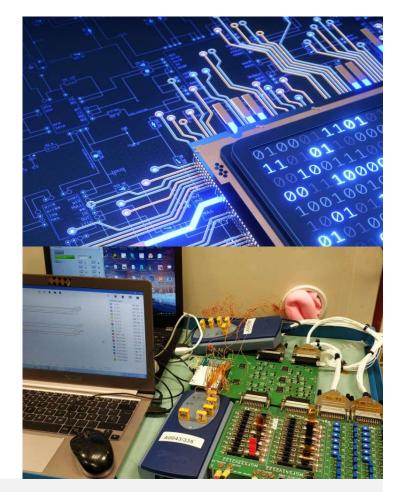
Includes all qualification steps in compliance with the Manufacturing Plan Standard and Pilot Circuit Procurement Specification.

The Pilot Circuit is submitted to the silicon qualification flow.

Qualification foreseen on the Pilot Circuit, after successful validation of the electrical and radiation specification.

For each of these IPs and for Pilot Circuit, its qualification status will include

- □ usage restrictions and/or recommendations
- production yield
- □ drift during screening and HTOL.





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PROMISE Project Conclusions



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Conclusions

PROMISE targets to become an ecosystem built around an IP Library qualified for Space usage

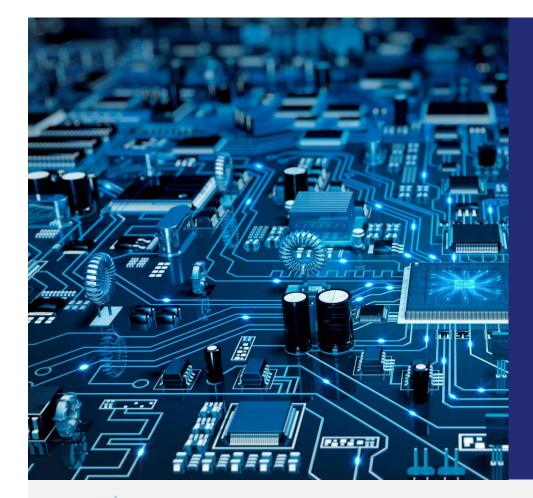
✓ Faster, Cheaper, Lower Risk Mixed Signal ASICs can be manufactured

✓ Participation is open for End Users, Supply Chain actors, Technology and Design providers

Contributions and cooperation will build a stronger community and benefit the contributors

✓ Further IP library details will be shown on final CUG workshop presenting project results & outcomes.





Thank you





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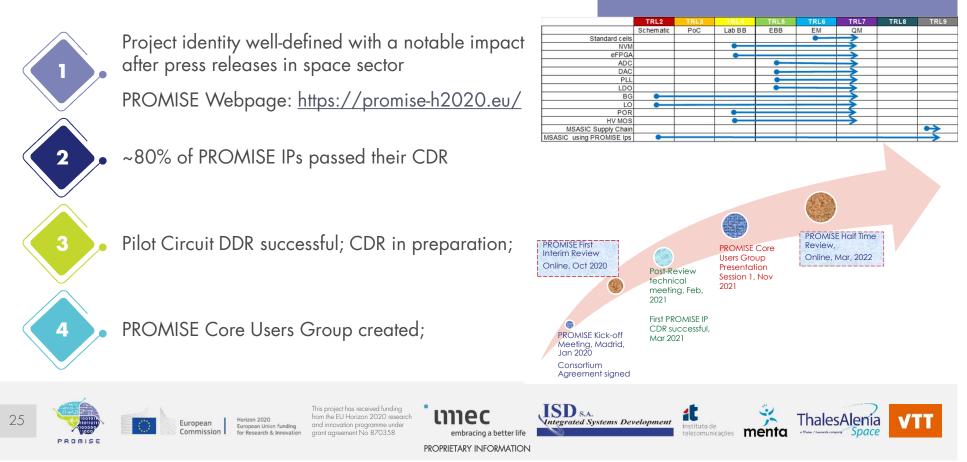








Main achievements



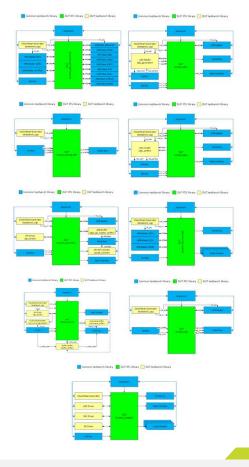
RTL Verification Plan

- 8 Unitary test benches + 1 Global test bench ٠
- 69 test cases ٠
- Verification status •
- Code coverage ٠
- ٠

: 100% PASS

- : 100% COVERAGE
- Reference document : [0005-0015514539] PROMISE PILOT CIRCUIT ASIC VERIFICATION PLAN (29/03/2022)

Design Scope <	Hits % •	Coverage % ◄	Total Coverage: (F	iltering A	Active)			85.88%	100.00%
i_dut	100.00%	100.00%	Coverage Type ◄	Bins 🖪	Hits 🖪	Misses 4	Weight 4	% Hit ◄	Coverage •
i propici top 0	100.00%	100.00%	Statements	2072	2072	0	1	100.00%	100.00%
			Branches	1346	1346	0	1	100.00%	100.00%
			FEC Expressions	139	139	0	1	100.00%	100.00%
			FEC Conditions	281	281	0	1	100.00%	100.00%
			FSMs	236	236	0	1	100.00%	100.00%
			States	87	87	0	1	100.00%	100.00%
			Transitions	149	149	0	1	100.00%	100.00%





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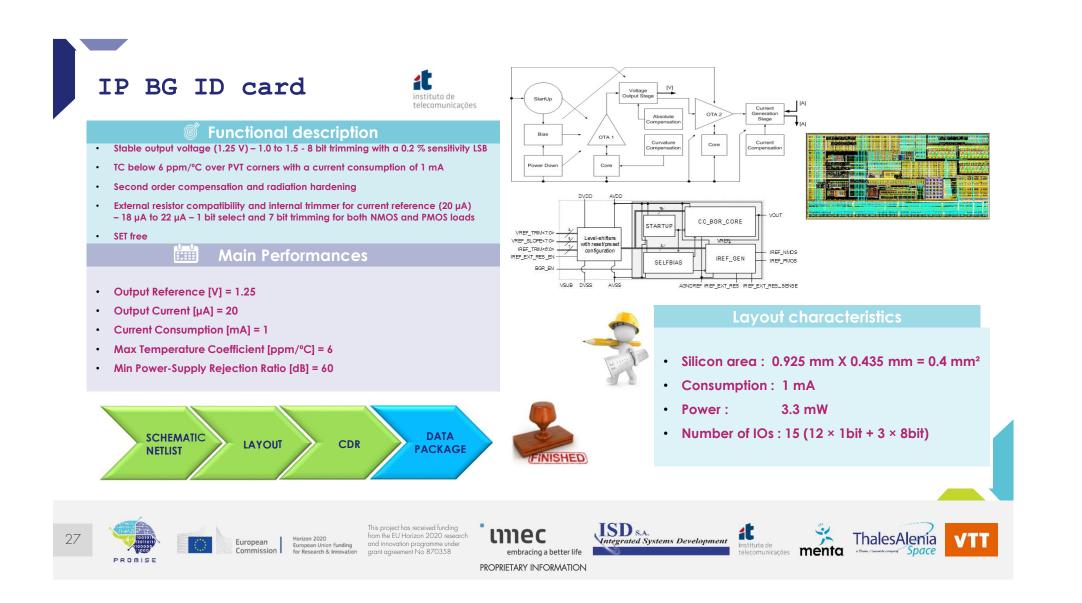


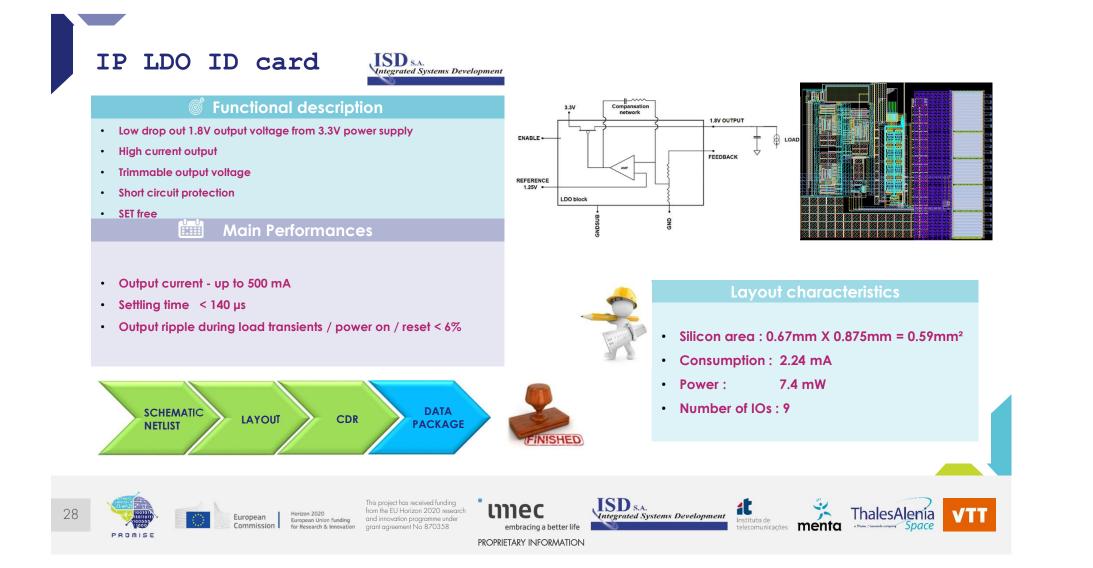


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26





IP POR

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Functional description

- Two independent POR devices supporting 3.3V/1.8V power supply (PS) domains
- BG voltage reference for accurate POR signal generation
- Delay added before POR signal released
- Undervoltage pulse filter
- SET free

Main Performances

- Valid PS voltage ranges = 3.3V-5%/+10% and $1.8V \pm 10\%$
- POR released/undervoltage corners = 3.1V/2.9V and 1.60V/1.52V

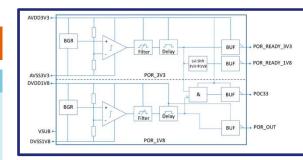
LAYOUT

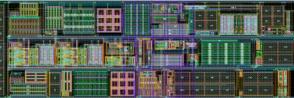
- Compatible with PS rise times = 10ns...100ms
- Min POR delay = 100 µs
- UV pulse filter = 10 ns

SCHEMATIC

NETLIST

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Layout characteristics

- Silicon area : 641µm x 209µm
- Consumption: 0.3 mA
- Power: 1 mW
- Number of IOs : 17



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CDR

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DATA

PACKAGE

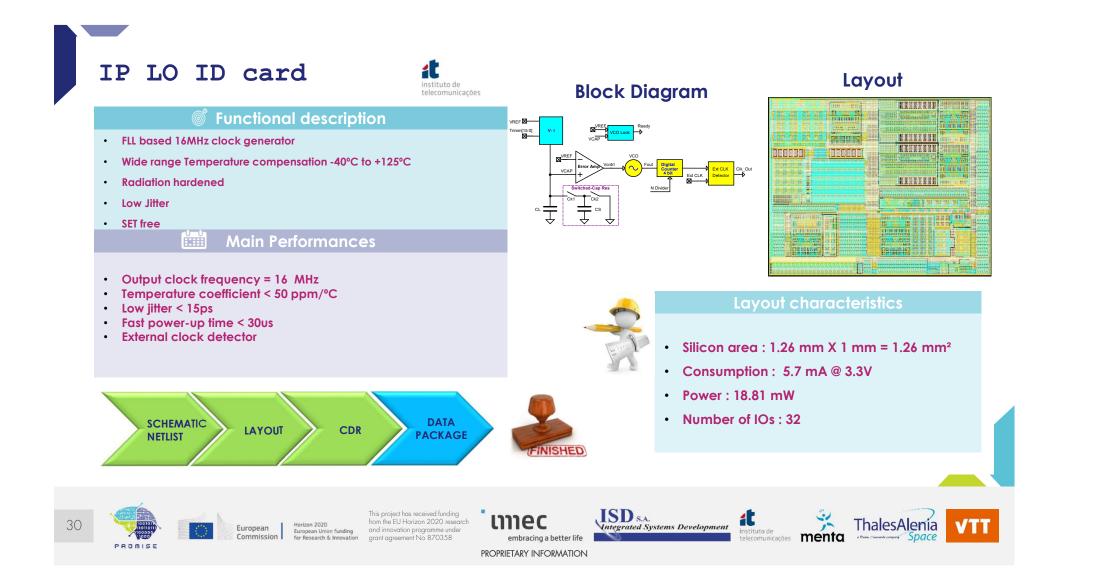


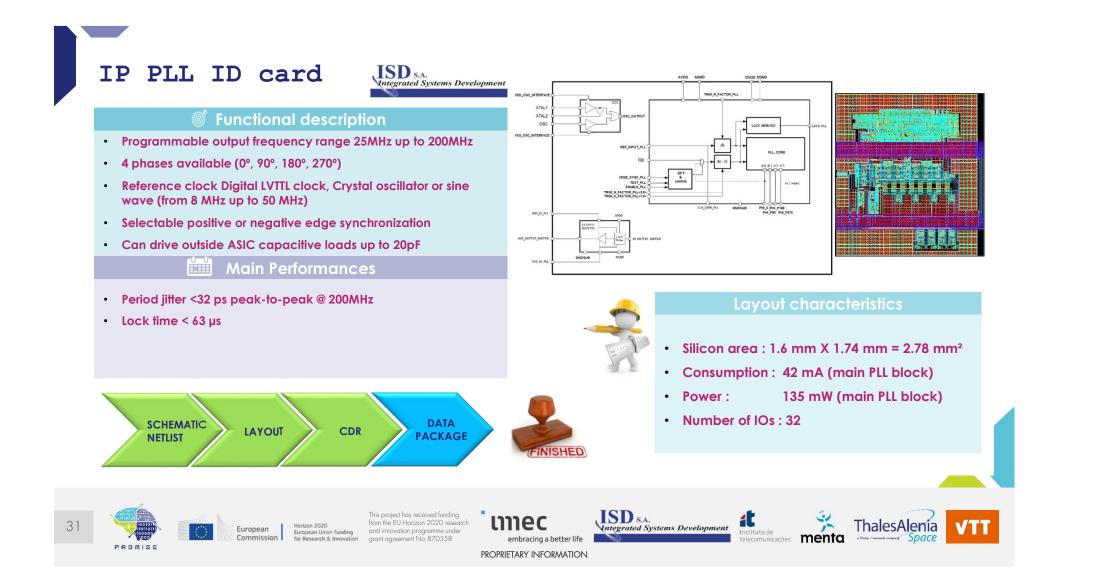




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INISHED





Next Steps (2/2)

					2	020								2	021								20	122								20	023				
	Work program	1 2	3	4 5	6	7	8 9	10	11 1	12 1	2	3	4 5	6	7	8 9	9 10	11	12 1	2	3	4 :	56	7	89	10		2 1	2	3	4 5	6	1	8	9 10	11	12
		1 2	3	4 5	6	7	8 9	10	11 1	12 1	3 14	15	16 1	7 18	19	20 2	1 22	23	24 25	5 26	27	28 2	9 30	31	32 33	34	35 3	6 37	38	39	40 41	42	43	44	45 46	i 47	48
	rary and Pilot Circuit specification	4							_		_			-		_	_		_	_			_				_	_	-		_				_		_
1.1 TASF 1.2 TASF	Establish standards for Mixed Signal IP Cores Design	_			_		_		_	_	_		_			_	_		_	_		_	_		_		_	_	-		_	-					
1.2 TASE 1.3 TASE	IPs Specification Pilot Circuit Specification	-								-	_												-					-				-					
1.3 TASE 1.4 IMEC	Plot Circuit Specification Ps Format Definition and Validation Checks	++-														-	_						-					-			_	-				-	
	Pilot Circuit Development																										_	-			_	-				-	
2.1 IMEC	Standard Cells and IOs Hardened Design, + LVDS	4																					-					-	-		-	-					
2.1 INEC	Analog IP BG Hardened Design	_																					-		_		-	-	-		-	-					
22 IT	Analog IP LO Hardened Design	++-																					-					-	-		-						
2.3 ISD	Analog IPs ADC Hardened Design	++-			-									-														-			-						_
2.3 ISD	Analog IPs DAC Hardened Design																																				
2.3 ISD	Analog IPs LDO 1V8 Hardened Design																							+													
2.3 ISD	Analog IPs PLL Hardened Design																																				
2.4 VTT	Analog IPs (POR) Hardened Design																																				
1.5 IMEC	NVM Hardened Design																																				
2.5 IMEC	HV cells Hardened Design																																				
2.6 MENTA	eFPGA Hardened Design																																				
2.7 TASF	Pilot Circuit Top Level Hardened Front-end Design																																				
2.8 IMEC	Pilot Circuit Top Level Hardened Back-end Design																							GDSI													
VP3 TASF SUPPL	Y CHAIN DEFINITION																																				
3.1 TASF	Define manufacturing plan standard																																				
3.2 TASF	Define Qualification Plan Standard																														month	margin	for Pilo	ot Circu	it subst	rat lead t	time
3.3 TASF	Identify European actors space mixed ASIC supply chain	\downarrow																												Ŷ							
3.4 TASF	Define Supply Chain for Pilot Circuit																																				
	rcuit MANUFACTURING																						1														
4.1 IMEC	Foundry of Pilot Circuit																						Y														
4.2 TASF/Supply Chain	Design Package for the Pilot Circuit :																										2 month o	design +		n lead tim							
4.3 TASF/Supply Chain	Industrialization of Pilot Circuit	++									_																		Test	solutor			1				
4.4 TASF/Supply Chain	Manufacturing Pilot Circuit	++															_						_							(2	weeks					2 margir	1
4.4 TASF/Supply Chain	Manufacturing Pilot Circuit	<u>++-</u>																														Asser	mbly 8	weeks			
	rcuit TEST AND QUALIFICATION																																				
5.1 TASE	Test Board Design and Manufacturing	++	+				_	+			+	$\left \right $			+		+			+			_	\vdash	_											+	
5.2 TASE	Electrical and radiation tests of Pilot Circuit		+		_	++	_	+			_	$\left \right $			++		_	+			\vdash		_	\vdash	_	\vdash			-							<u> </u>	
5.3 TASF/Supply Chain	Qualification of Pilot Circuit : screening		+			++					_	+			++	_	_	+					_	\vdash		+	_							Screenin	ng : 2 m	onths avai	ilable : 1 m
5.3 TASF/Supply Chain	Qualification of Pilot Circuit																													-	-						



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